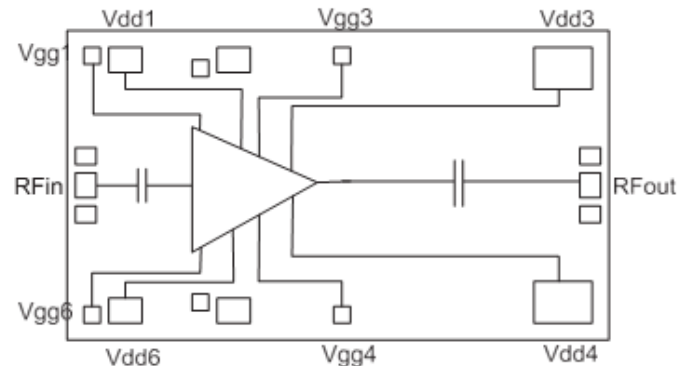


**Features**

- Frequency: 6-18GHz
- Gain: 23dB
- P1dB: 33dBm
- OIP3: +40dBm
- Power Supply : +8.0V@1150mA
- Die Size : 4.68 x 2.84 mm

**Typical Applications**

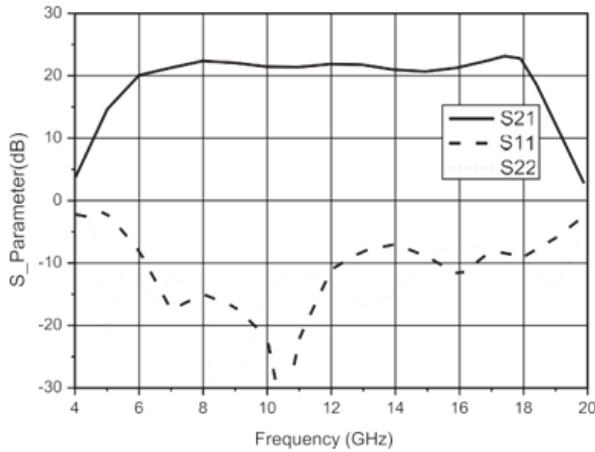
- Test Instrumentation
- Microwave Radio & VSAT
- Military & Space
- Telecom Infrastructure
- Fiber Optics

**Functional Block Diagram**

**Electrical Specifications**

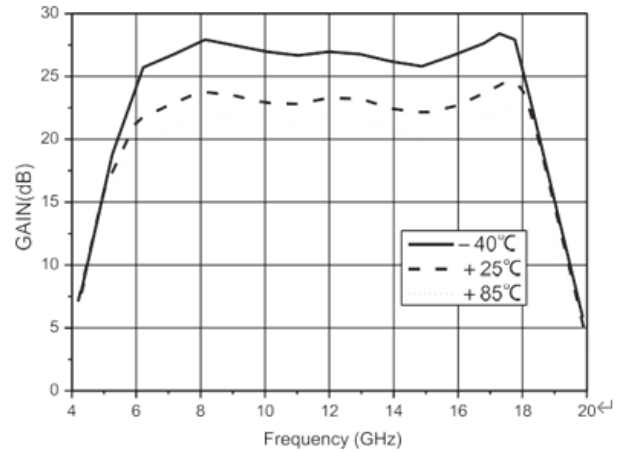
TA = +25°C, Vdd = +8V, Vgg = -0.67V (On-wafer Measurement Results)

Parameters	Min.	Typ.	Max.	Units
Frequency	6-18			GHz
Gain		23		dB
Gain Flatness		±1.5		dB
P1dB		33		dBm
OIP3		40		dBm
Psat		35		dBm
PAE		26		%
Input Return Loss		14		dB
Output Return Loss		17		dB
Operating Current		1150		mA

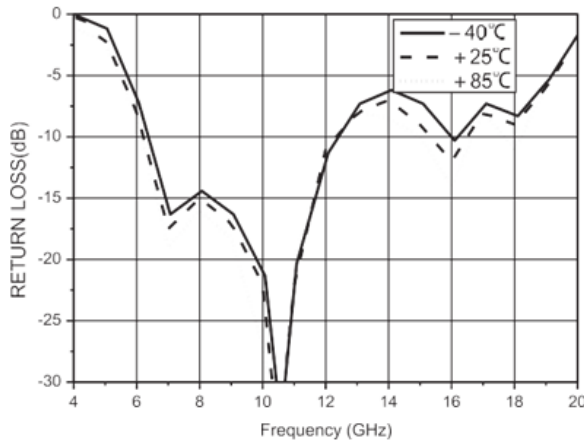
**S-Parameter vs. Frequency**



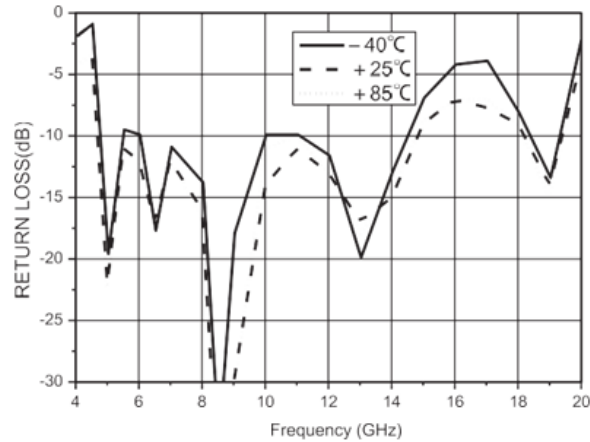
**Gain vs. Temperature**



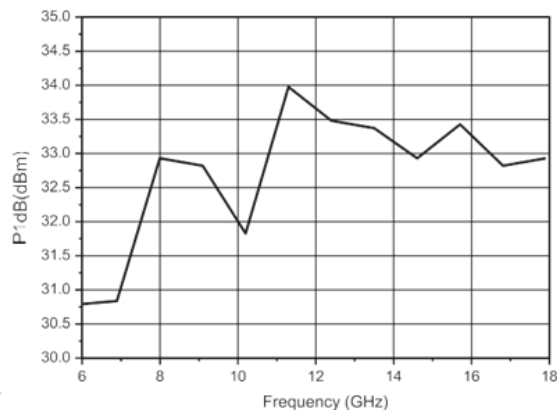
**Input Return Loss vs. Temperature**



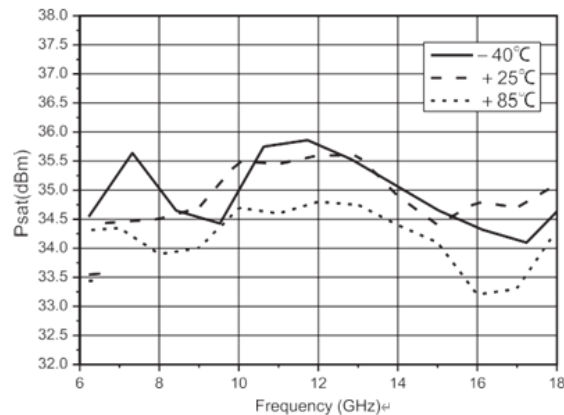
**Output Return Loss vs. Temperature**



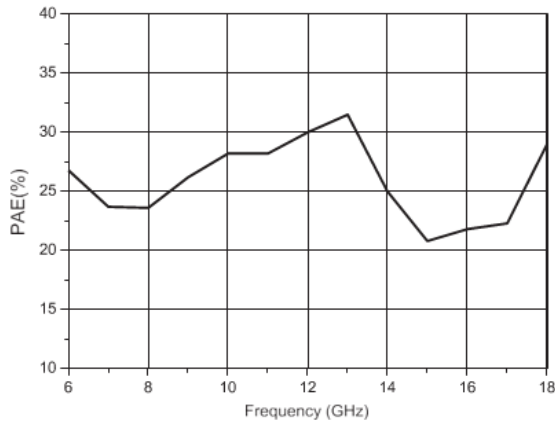
**P1dB vs. Frequency**



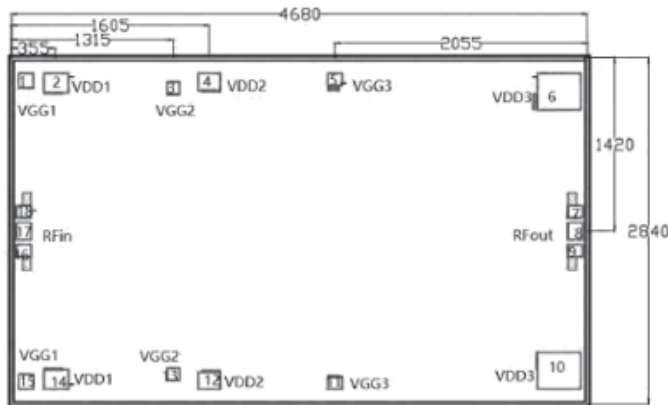
**Psat vs. Temperature**



**PAE at Psat vs. Frequency**



**Outline Drawing:**  
All Dimensions in  $\mu\text{m}$

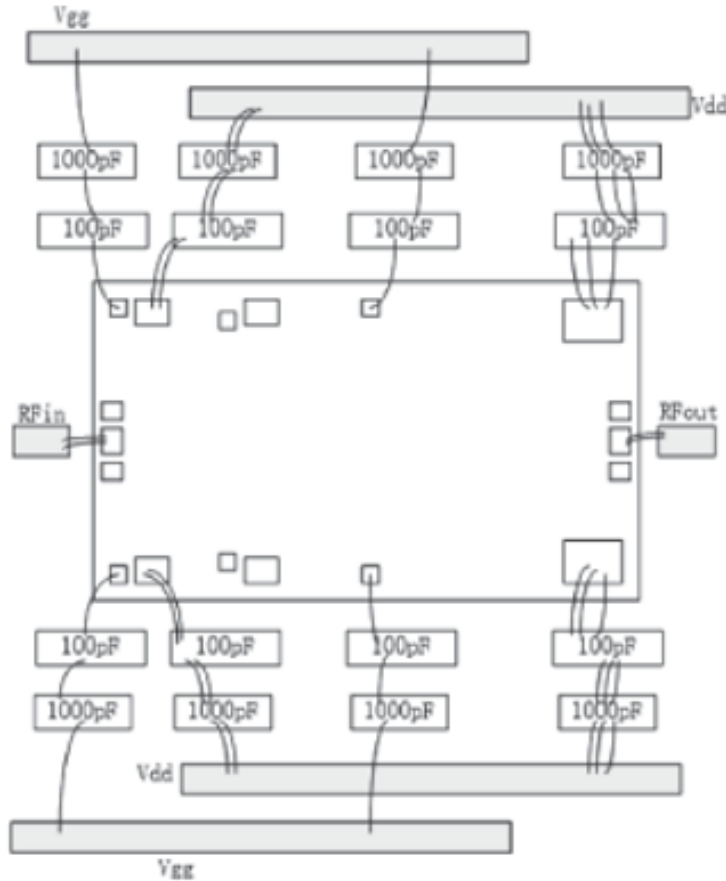


**Pad Description**

Pad	Function	Description
17	RF IN	Signal input terminal, connected to 50 $\Omega$ circuit.
8	RF OUT	Signal output terminal, connected to 50 $\Omega$ circuit.
2,4,6,10,12,14	Vdd	Amplifier power supply; external 100pF capacitor required.
1,3,5,11,13,15	Vgg	Amplifier gate control power supply, and the current can be changed by applying different gate voltages.
7,9,16,18	GND	Die bottom must be connected to RF/DC ground.



### Assembly Drawing (Bond testing)



#### Notes:

1. Die thickness: 100um
2. Typical bond pad is 100\*100  $\mu\text{m}^2$
3. Bond pad metalization: Gold
4. Backside metalization: Gold
5. Backside of the die (GND)
6. No connection required for unlabeled bond pads

#### Maximum Ratings:

1. Supply voltage: +9V
2. RF Input power: +16dBm
3. Operating temperature: -55°C to +85°C
4. Storage temperature: -65°C to +150°C